

“Fast versus conventional HAADF-STEM tomography of nanoparticles: advantages and challenges”. Vanrompay H, Skorikov A, Bladt E, Béch   A, Freitag B, Verbeeck J, Bals S, Ultramicroscopy **221**, 113191 (2021). <http://doi.org/10.1016/j.ultramic.2020.113191>